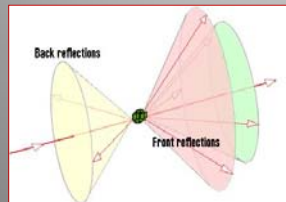


PHYS485 Materials Physics

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X-ray Methods

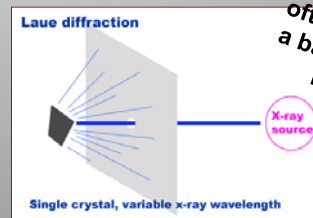
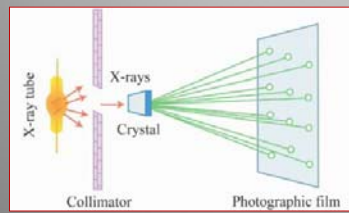
- The Laue Method: scatter from single Xtal using range of wavelengths from λ_1 to λ_0
- The Rotating Crystal Method: monochromatic X-rays with rotating sample
- The Powder (Debye-Sherrer) Method: equivalent to rot. Xtal method but with rot. axis varied over all possible orientations



$$G = 2k \sin(\phi / 2) = 2k \sin(\theta)$$

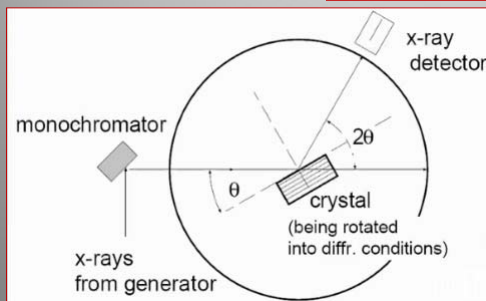
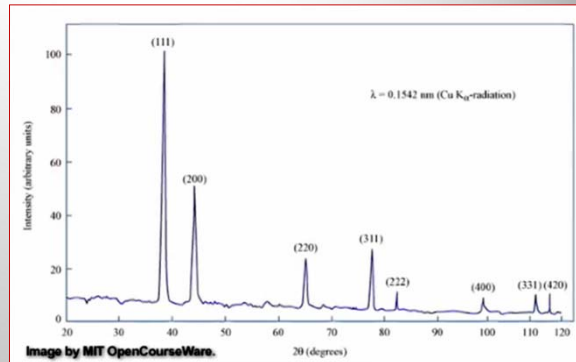
Note: scattering angle $\phi \equiv 2\theta$
where θ is the Bragg angle

- XRD: Laue pattern:
 - white X-rays; do not know λ
 - useful for orienting Xtals



often used in a backscatter mode

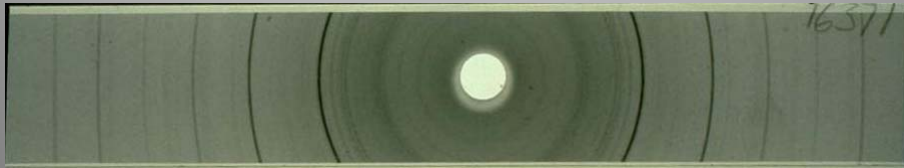
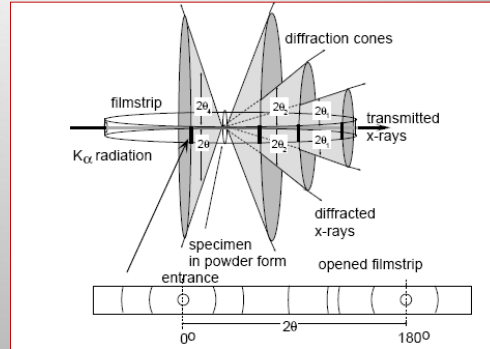
XRD: Rotating Xtal



Note:
 $\phi \equiv 2\theta$

XRD: Powder Method

- Debye-Scherrer method



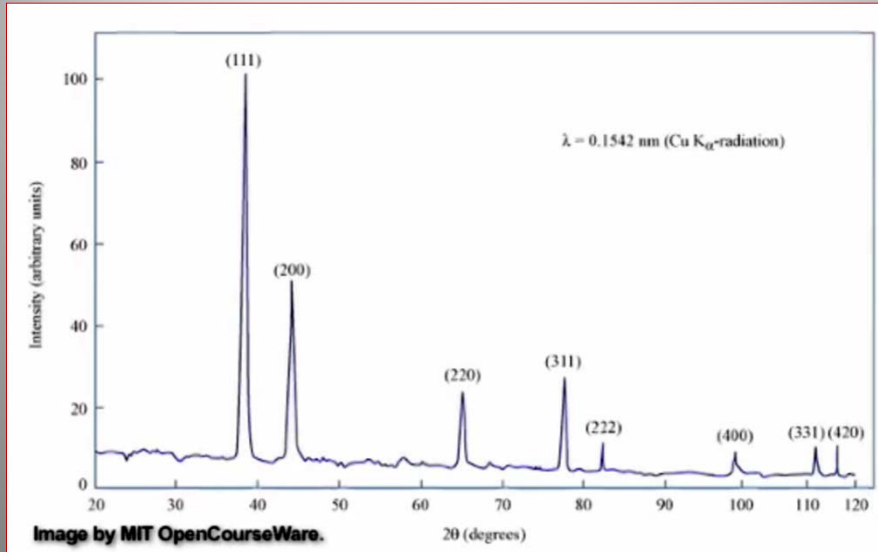
XRD Selection Rule Chart for reflection in cubic systems

- SC: all allowed
- BCC: $h + k + l = \text{even}$
- FCC: h, k, l all even or all odd ("unmixed")
- Diamond? **FCC + basis**

(hkl)	$h^2+k^2+l^2$	SC	BCC	FCC
100	1	Y	N	N
110	2	Y	Y	N
111	3	Y	N	Y
200	4	Y	Y	Y
210	5	Y	N	N
211	6	Y	Y	N
220	8	Y	Y	Y
300	9	Y	N	N
310	10	Y	Y	N
311	11	Y	N	Y
222	12	Y	Y	Y
320	13	Y	N	N
321	14	Y	Y	N
400	16	Y	Y	Y

Diamond: the red circled FCC bits + (331)

Rotating Xtal data:



One method of attack:

- (1) Start with 2θ values and generate a set of $\sin^2\theta$ values.
- (2) Normalize the $\sin^2\theta$ values by generating $\sin^2\theta_n/\sin^2\theta_1$
- (3) Clear fractions from the “normalized” column.
- (4) Speculate on the hkl values that would seem as $h^2+k^2+l^2$ to generate the sequence of the “clear fractions” column.
- (5) Compute for each θ the value of $\sin^2\theta/(h^2+k^2+l^2)$ on the basis of the assumed hkl values. If each entry in this column is identical, then the entire process is validated.

Diffraction with Real Atoms

- The amplitude of a scattered wave is given by

$$A \propto \left[\sum_R \exp(i\vec{R} \cdot \Delta\vec{k}) \right] \left[\sum_p f_{ap}(\theta) \exp(i\vec{r}_p \cdot \Delta\vec{k}) \right]$$

or $A \propto \sum_R e^{i\vec{R} \cdot \vec{G}} S_{\vec{k}}$ for **constructive interference**

[We'll show this shortly!]

[\vec{R} points to unit cells, \vec{r}_p to atoms in unit cell; \vec{r}' is the integration variable for e- density]

where $S_{\vec{G}} = \sum_p f_{ap}(\theta) e^{i\vec{G} \cdot \vec{r}_p}$ = geometric structure factor

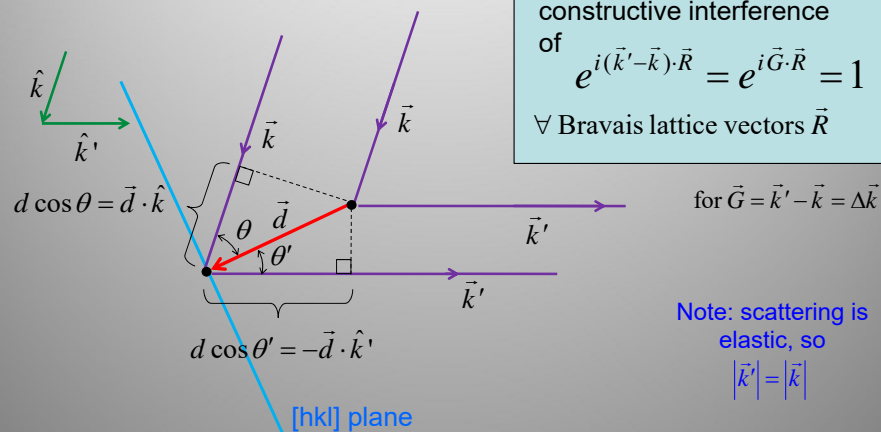
$$f_{ap}(\theta) = f_e(\theta) \int_p \rho(\vec{r}') \exp(i\vec{r}' \cdot \Delta\vec{k}) d^3\vec{r}'$$

$f_{ap}(\theta)$ is the **atomic form factor** (atomic scattering function)

$f_e(\theta)$ is the **electron form factor** (electron scattering function)

Back to X-rays! Laue formulation:

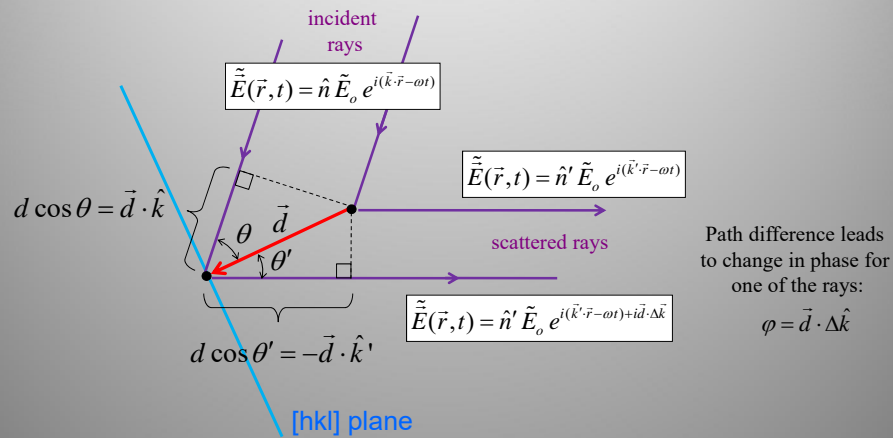
Path difference: $d \cos \theta + d \cos \theta' = \vec{d} \cdot (\hat{k} - \hat{k}') = m\lambda$



Laue formulation:

The intensity of an electromagnetic wave is proportional to the amplitude of the electric field; for the incident rays

$$I \propto \left| \tilde{\vec{E}}_o e^{i(\vec{k} \cdot \vec{r} - \omega t)} \right|^2 \\ = \left| \tilde{\vec{E}}_o e^{i\vec{k} \cdot \vec{r}} e^{-i\omega t} \right|^2 = \left| \tilde{\vec{E}}_o e^{i\vec{k} \cdot \vec{r}} \right|^2$$



Laue formulation:

The intensity of the scattered electromagnetic wave is superposition of x-rays scattered by the two atoms:

$$\tilde{\vec{E}}(\vec{r}, t) = \hat{n}' \tilde{E}_o e^{i(\vec{k}' \cdot \vec{r} - \omega t)} + \hat{n}' \tilde{E}_o e^{i(\vec{k}' \cdot \vec{r} - \omega t) + i\vec{d} \cdot \Delta \vec{k}}$$

So we have

$$I_{scatt} \propto \left| e^{i(\vec{k}' \cdot \vec{r} - \omega t)} + e^{i(\vec{k}' \cdot \vec{r} - \omega t) + i\vec{d} \cdot \Delta \vec{k}} \right|^2 = \left| e^{i\vec{k}' \cdot \vec{r}} + e^{i\vec{k}' \cdot \vec{r}} e^{i\vec{d} \cdot \Delta \vec{k}} \right|^2 \\ = \left| e^{i\vec{k}' \cdot \vec{r}} (1 + e^{i\vec{d} \cdot \Delta \vec{k}}) \right|^2 = \left| 1 + e^{i\vec{d} \cdot \Delta \vec{k}} \right|^2$$

If the second term is -1, then we have completely **destructive interference**;

if the second term is +1, then we have completely **constructive interference**

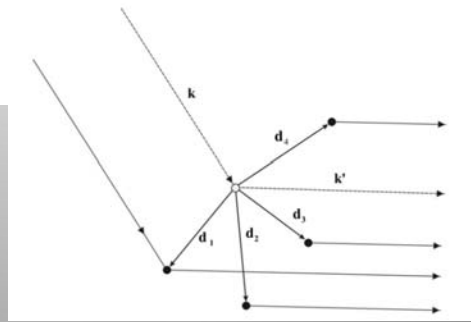
Laue formulation:

For multiple scattering – from more than two atoms:

$$\begin{aligned} \left| \tilde{E}'(\vec{r}, t) \right| &\sim e^{-(\vec{k}' \cdot \vec{r} - \omega t) + i\vec{d}_0 \cdot \vec{K}} + e^{-(\vec{k}' \cdot \vec{r} - \omega t) + i\vec{d}_1 \cdot \vec{K}} + \\ &e^{-(\vec{k}' \cdot \vec{r} - \omega t) + i\vec{d}_2 \cdot \vec{K}} + e^{-(\vec{k}' \cdot \vec{r} - \omega t) + i\vec{d}_3 \cdot \vec{K}} + \\ &e^{-(\vec{k}' \cdot \vec{r} - \omega t) + i\vec{d}_4 \cdot \vec{K}} \\ &= e^{-(\vec{k}' \cdot \vec{r} - \omega t)} \left(\sum_{j=0}^4 e^{i\vec{d}_j \cdot \vec{K}} \right) \end{aligned}$$

If all the scattering centers are identical, we define the *Structure Factor*:

$$S(\vec{d}_j, \Delta\vec{k}) = \sum_{j=0}^4 e^{i\vec{d}_j \cdot \Delta\vec{k}}$$



So, we have $I_{scatt} \propto \left| \tilde{E}'(\vec{r}, t) \right|^2 \propto \left| S(\vec{d}_j, \Delta\vec{k}) \right|^2$

Laue formulation:

In general, if all the scattering are not the same, we write the *Structure Factor* as:

$$S(\vec{d}_j, \Delta\vec{k}) = \sum_{j=0}^4 f_{aj}(\Delta\vec{k}) e^{i\vec{d}_j \cdot \Delta\vec{k}}$$

where $f_{aj}(\Delta\vec{k})$ is the *atomic form factor* (atomic scattering function) and the sum is over the atoms in the unit cell. Thus, we have

$$I_{scatt} \propto \left| \tilde{E}'(\vec{r}, t) \right|^2 \propto \left| S(\vec{d}_j, \Delta\vec{k}) \right|^2$$

If $\Delta\vec{k} = \vec{k}' - \vec{k} = \vec{G}$ then we have constructive interference!

For cubic structures, the $\vec{d}_j = \vec{a}_j$, our lattice vectors, with

$$\vec{G} = m_1 \frac{2\pi}{a} \hat{i} + m_2 \frac{2\pi}{a} \hat{j} + m_3 \frac{2\pi}{a} \hat{k} \quad \vec{a}_i \cdot \vec{G} = 2\pi m_i$$

Laue Formulation



Note that $\vec{a}_i \cdot \vec{G} = 2\pi m_i$ for integer m_i

So $\vec{R} \cdot \vec{G} = 2\pi n$ for integer n

or

$$e^{i\vec{G} \cdot \vec{R}} = 1$$

Laue condition for
constructive
interference

The **reciprocal lattice** is the set of all vectors \vec{G} satisfying this relation for all \vec{R} in the Bravais lattice.

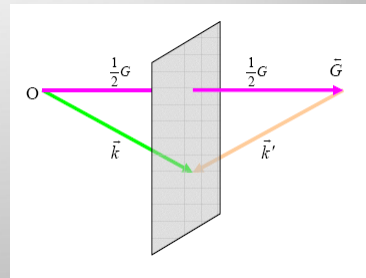
Laue formulation – alternate form

$$\vec{k} \cdot \hat{G} = \frac{1}{2}G$$

The component of the incident wavevector along G is equal to half the "length" of G

Laue condition satisfied **iff** the tip of the incident wavevector lies in a plane that is the perp. bisector of a line joining the origin of k -space to a reciprocal lattice point.

These planes are referred to as **BRAGG PLANES**



Diffraction: constructive interference

- Laue Formulation vs. Bragg Condition: One can show that they are equivalent!
- Combining these tools with an understanding of the reciprocal lattice, one can interpret XRD data

$$|\vec{G}| = \frac{2\pi}{d} = \sqrt{h^2 + k^2 + l^2} \quad 2d \sin \theta = n\lambda$$

Mechanical Properties

- Tension/Compression

➤ Stress $\sigma = \frac{F}{A}$

➤ Strain $\varepsilon = \frac{\Delta l}{l}$

➤ Related by $\sigma = Y\varepsilon$

where Y is Young's modulus
(the gradient of a σ vs. ε plot)



A property of the material;
independent of size/shape!

